

60V N-Channel Enhancement Mode MOSFET

Description

The AP3N06I uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 60V$ $I_D = 3A$

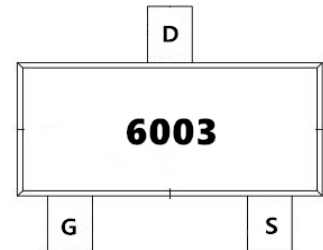
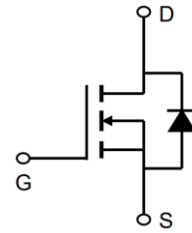
$R_{DS(ON)} < 100m\Omega$ @ $V_{GS}=10V$

Application

Battery protection

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

| Product ID | Pack | Marking | Qty(PCS) |
|------------|--------|---------|----------|
| AP3N06I | SOT-23 | 6003 | 3000 |

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Rating | Units |
|----------------------------|--|------------|--------------------|
| V_{DS} | Drain-Source Voltage | 60 | V |
| V_{GS} | Gate-Source Voltage | ± 20 | V |
| $I_D@T_A=25^\circ\text{C}$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 3.0 | A |
| $I_D@T_A=70^\circ\text{C}$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 1.8 | A |
| I_{DM} | Pulsed Drain Current ² | 9.2 | A |
| $P_D@T_A=25^\circ\text{C}$ | Total Power Dissipation ³ | 1 | W |
| T_{STG} | Storage Temperature Range | -55 to 150 | $^\circ\text{C}$ |
| T_J | Operating Junction Temperature Range | -55 to 150 | $^\circ\text{C}$ |
| $R_{\theta JA}$ | Thermal Resistance Junction-Ambient ¹ | 125 | $^\circ\text{C/W}$ |
| $R_{\theta JC}$ | Thermal Resistance Junction-Case ¹ | 80 | $^\circ\text{C/W}$ |



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Electrical Characteristics (T_A=25°C unless otherwise noted)

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|-------------------------------------|--|--|------|-------|------|-------|
| BV _{DSS} | Drain-Source Breakdown Voltage | V _{GS} =0V, I _D =250μA | 60 | --- | --- | V |
| ΔBV _{DSS} /ΔT _J | BV _{DSS} Temperature Coefficient | Reference to 25°C, I _D =1mA | --- | 0.054 | --- | V/°C |
| R _{DS(ON)} | Static Drain-Source On-Resistance ² | V _{GS} =10V, I _D =2A | --- | 80 | 100 | mΩ |
| | | V _{GS} =4.5V, I _D =1A | --- | 85 | 110 | |
| V _{GS(th)} | Gate Threshold Voltage | | 1.2 | --- | 2.5 | V |
| ΔV _{GS(th)} | V _{GS(th)} Temperature Coefficient | V _{GS} =V _{DS} , I _D =250μA | --- | -4.96 | --- | mV/°C |
| I _{DSS} | Drain-Source Leakage Current | V _{DS} =48V, V _{GS} =0V, T _J =25°C | --- | --- | 1 | μA |
| | | V _{DS} =48V, V _{GS} =0V, T _J =55°C | --- | --- | 5 | |
| I _{GSS} | Gate-Source Leakage Current | V _{GS} =±20V, V _{DS} =0V | --- | --- | ±100 | nA |
| g _{fs} | Forward Transconductance | V _{DS} =5V, I _D =2A | --- | 13 | --- | S |
| Q _g | Total Gate Charge (4.5V) | | --- | 5 | 7.0 | nC |
| Q _{gs} | Gate-Source Charge | V _{DS} =48V, V _{GS} =4.5V, I _D =2A | --- | 1.68 | 2.4 | |
| Q _{gd} | Gate-Drain Charge | | --- | 1.9 | 2.7 | |
| T _{d(on)} | Turn-On Delay Time | | --- | 1.6 | 3.2 | ns |
| T _r | Rise Time | V _{DD} =30V, V _{GS} =10V, R _G =3.3Ω, I _D =2A | --- | 7.2 | 13 | |
| T _{d(off)} | Turn-Off Delay Time | | --- | 25 | 50 | |
| T _f | Fall Time | | --- | 14.4 | 28.8 | |
| C _{iss} | Input Capacitance | | --- | 511 | 715 | pF |
| C _{oss} | Output Capacitance | V _{DS} =15V, V _{GS} =0V, f=1MHz | --- | 38 | 53 | |
| C _{rss} | Reverse Transfer Capacitance | | --- | 25 | 35 | |
| I _S | Continuous Source Current ^{1,4} | V _G =V _D =0V, Force Current | --- | --- | 2.3 | A |
| I _{SM} | Pulsed Source Current ^{2,4} | | --- | --- | 9.2 | A |
| V _{SD} | Diode Forward Voltage ² | V _{GS} =0V, I _S =1A, T _J =25°C | --- | --- | 1.2 | V |
| t _{rr} | Reverse Recovery Time | I _F =2A, di/dt=100A/μs, T _J =25°C | --- | 9.7 | --- | nS |
| Q _{rr} | Reverse Recovery Charge | | --- | 5.8 | --- | nC |

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%
- 3.The power dissipation is limited by 150°C junction temperature.
- 4.The data is theoretically the same as I_D and I_{DM}, in real applications, should be limited by total power dissipation.

Typical Characteristics

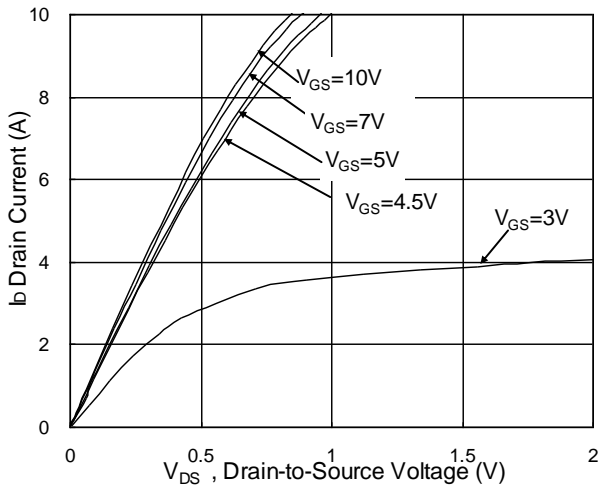


Fig.1 Typical Output Characteristics

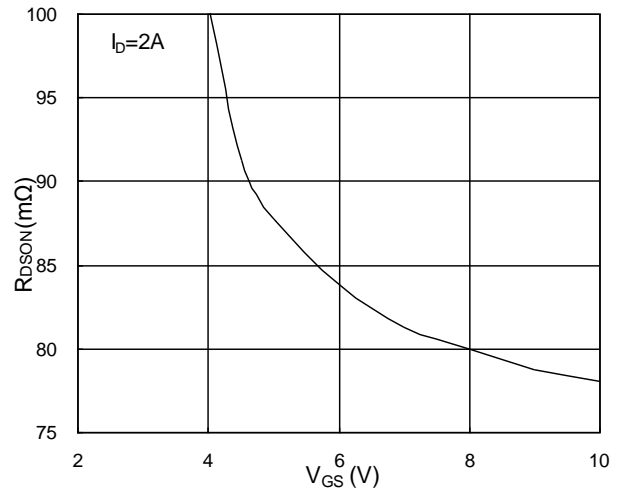


Fig.2 On-Resistance v.s Gate-Source

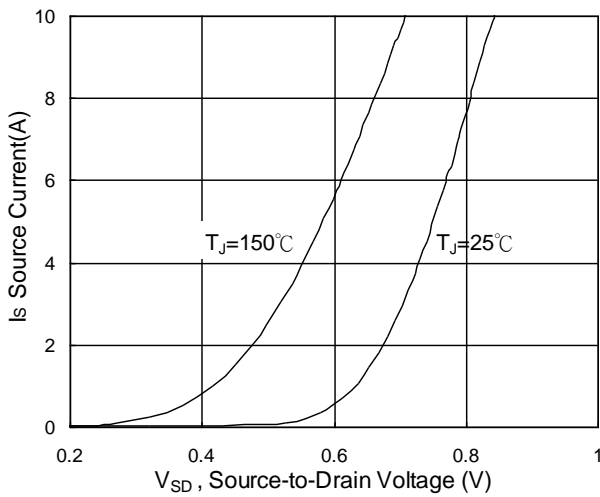


Fig.3 Forward Characteristics of Reverse

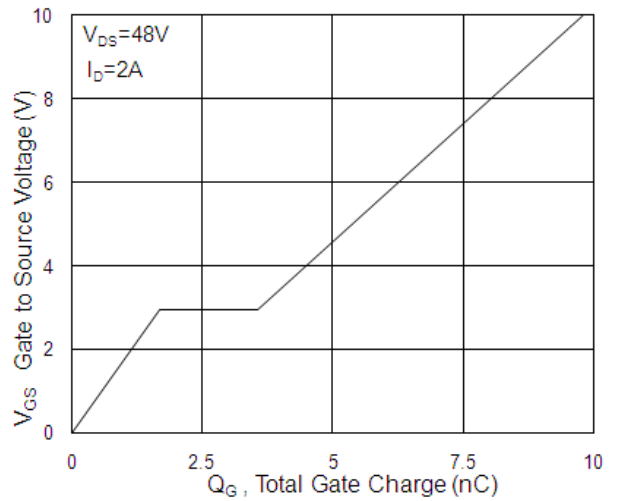


Fig.4 Gate-Charge Characteristics

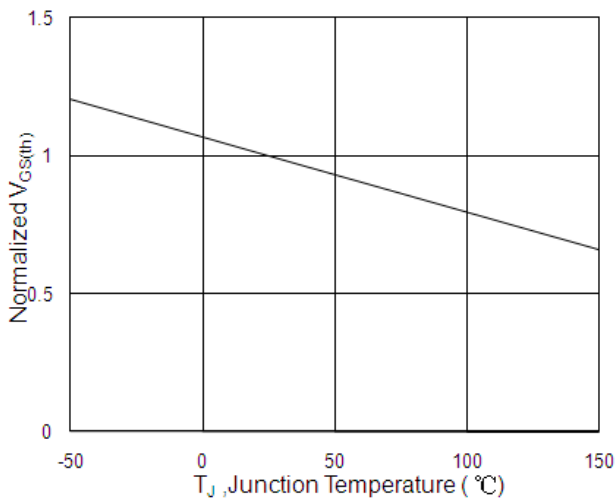


Fig.5 Normalized $V_{GS(th)}$ v.s T_J

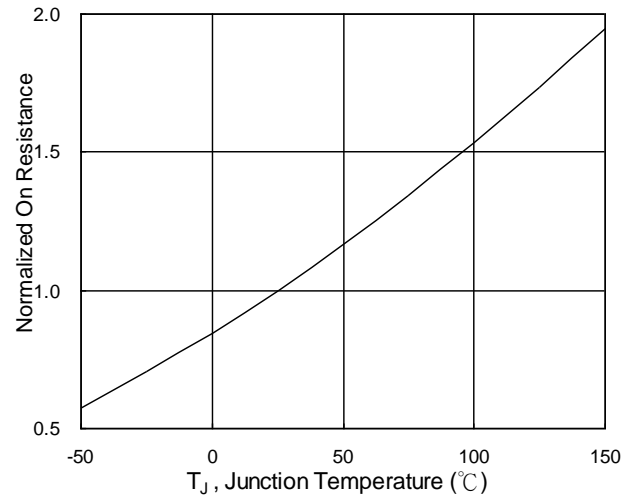


Fig.6 Normalized $R_{DS(on)}$ v.s T_J



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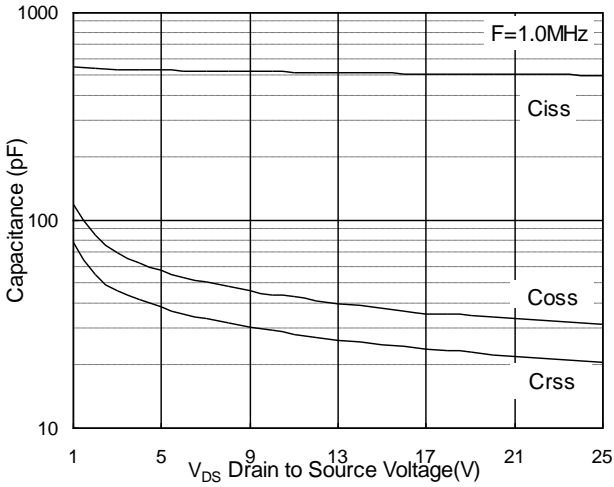


Fig.7 Capacitance

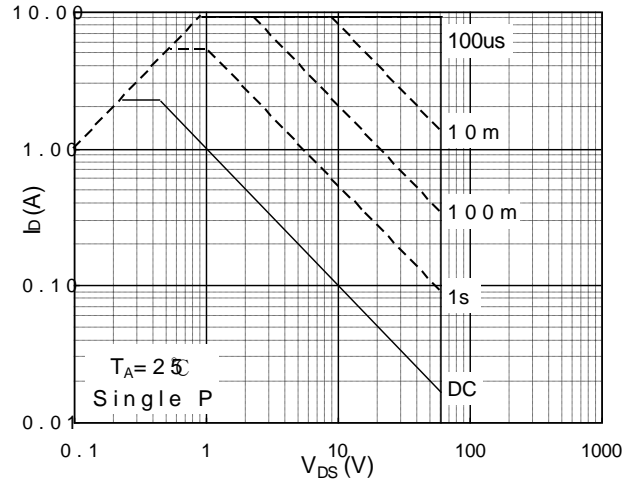


Fig.8 Safe Operating Area

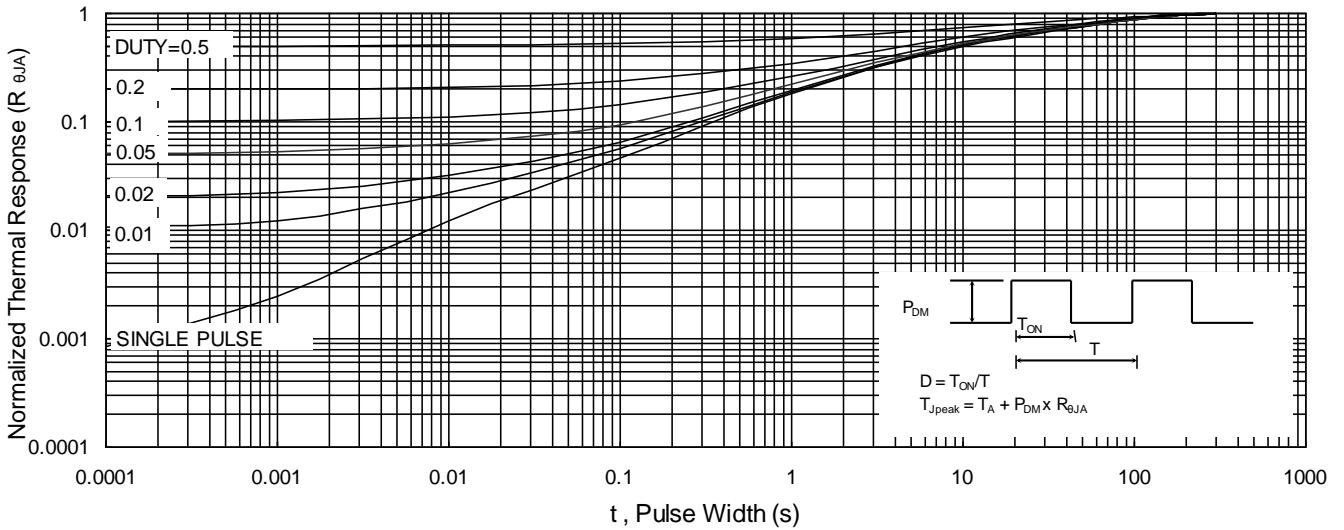


Fig.9 Normalized Maximum Transient Thermal Impedance

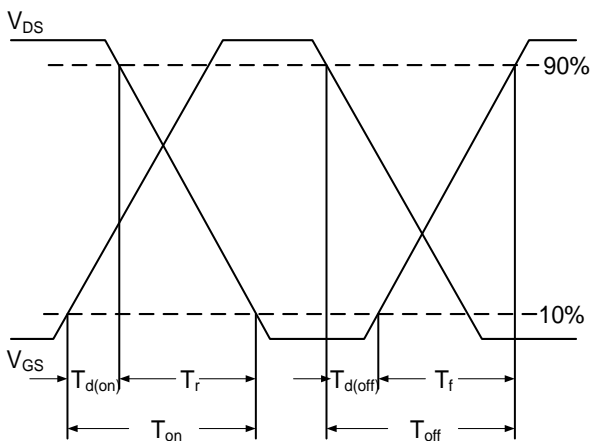


Fig.10 Switching Time Waveform

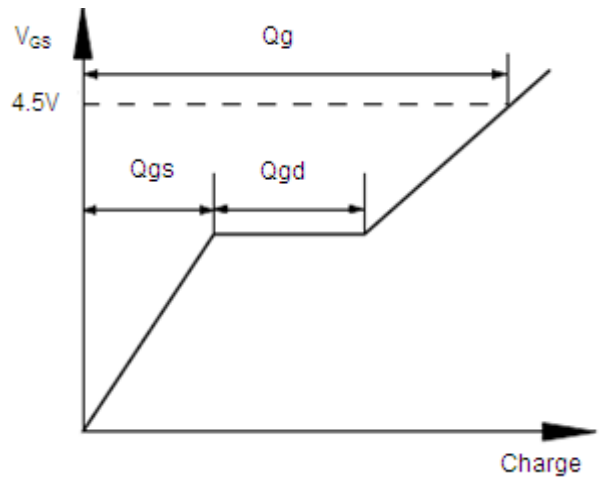
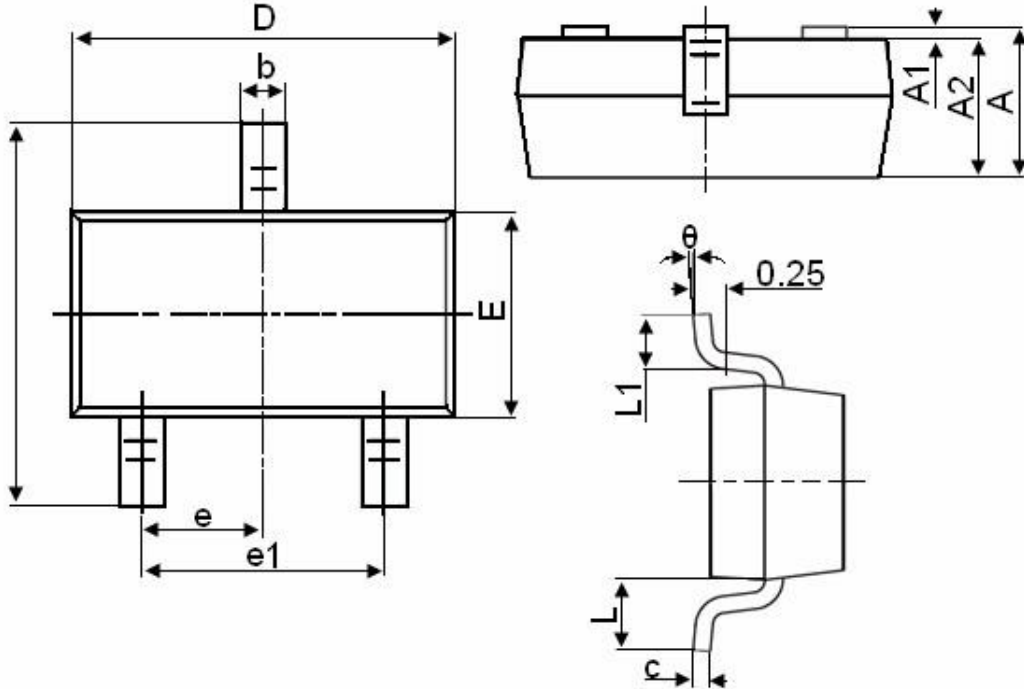


Fig.11 Gate Charge Waveform

Package Mechanical Data-SOT23



| Symbol | Dimensions in Millimeters | |
|----------|---------------------------|-------|
| | MIN. | MAX. |
| A | 0.900 | 1.150 |
| A1 | 0.000 | 0.100 |
| A2 | 0.900 | 1.050 |
| b | 0.300 | 0.500 |
| c | 0.080 | 0.150 |
| D | 2.800 | 3.000 |
| E | 1.200 | 1.400 |
| E1 | 2.250 | 2.550 |
| e | 0.950TYP | |
| e1 | 1.800 | 2.000 |
| L | 0.550REF | |
| L1 | 0.300 | 0.500 |
| θ | 0° | 8° |

60V N-Channel Enhancement Mode MOSFET**Attention**

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| Edition | Date | Change |
|---------|-----------|-----------------|
| Rve1.0 | 2019/5/31 | Initial release |

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